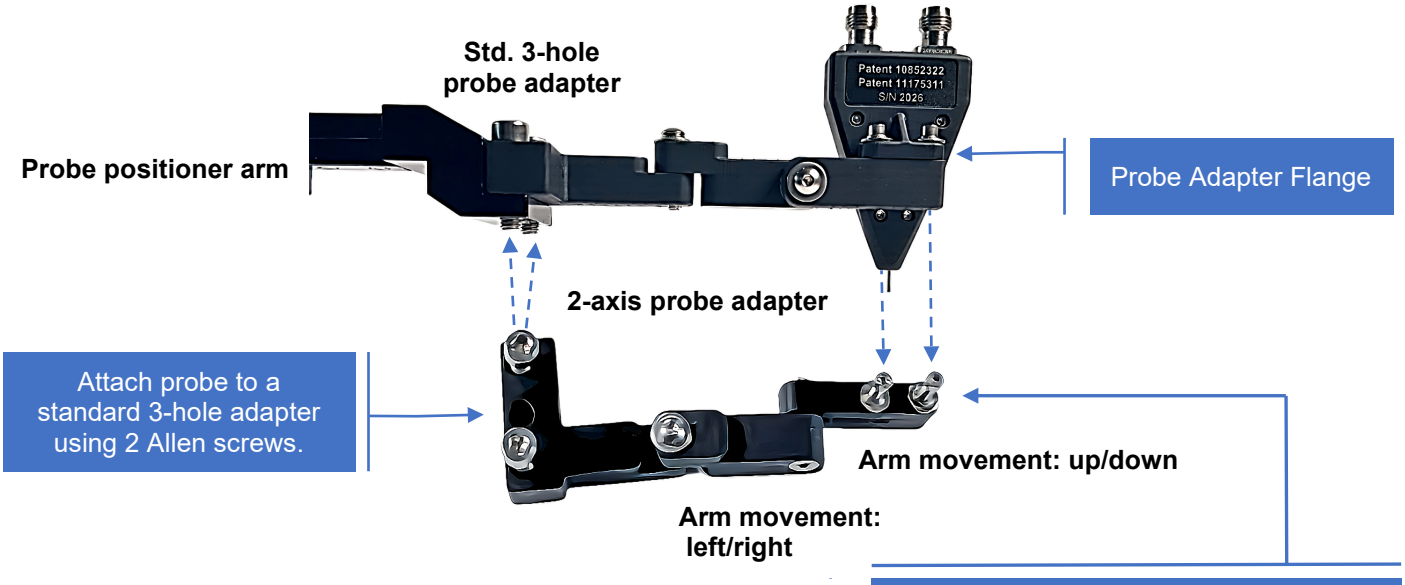
# 2-Axis DVT-FPPNN Probe Adapter

For DVT-FPPNN 40 GHz to 110 GHz Differential Probes


## Features

- **Easy assembly:** Attaches to standard 3-hole adapter
- **Extremely versatile:** Nine different configurations
- **Multi-angle**: Three probe orientations
- **Use for many probing applications**

## Assembling the DVT-FPPNN Probe to the 2-Axis Adapter




## Nine different configurations (Top-down view)

Horizontal: Side-by-side probing
- Arm is straight
- Probe can be on the left or right side
- Probe straight down

Vertical Probing: Vertically fixtured PCB
- Arm is straight
- Probe can be on the left or right side
- Probe is lifted to contact horizontally oriented test pads

Vertical probing:
- Arm is 90° to vertically fixtured PCB
- Probe is lifted to contact vertically oriented test pads

Horizontal probing:
- 90° oriented test pads on a horizontally fixtured PCB
- Probe can be on the left or right side
- Probe straight down

## Three orientations (Side view)


Horizontal Probing: Probe horizontally or vertically oriented test pads on horizontal fixtured PCB
- Probe can be on the left or right side
- Probe arm is in the straight position

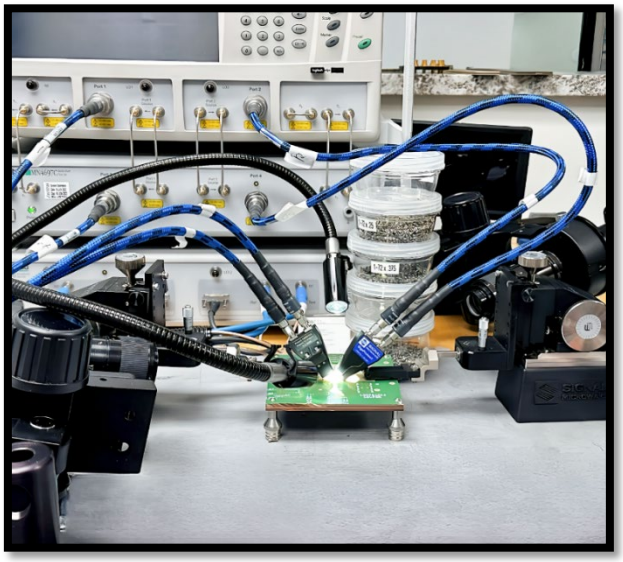

Vertical 90° Probing: Probe horizontally oriented test pads on a vertically fixtured PCB
- Probe can be on the left or right side
- Probe arm is lifted into position


Horizontal 45° probing: Horizontally fixtured PCB
- Probe into deep test sockets or face-to-face tight-pitched test pads
- Probe can be on the left or right side
- Probe arm is in the straight position

# APPLICATION

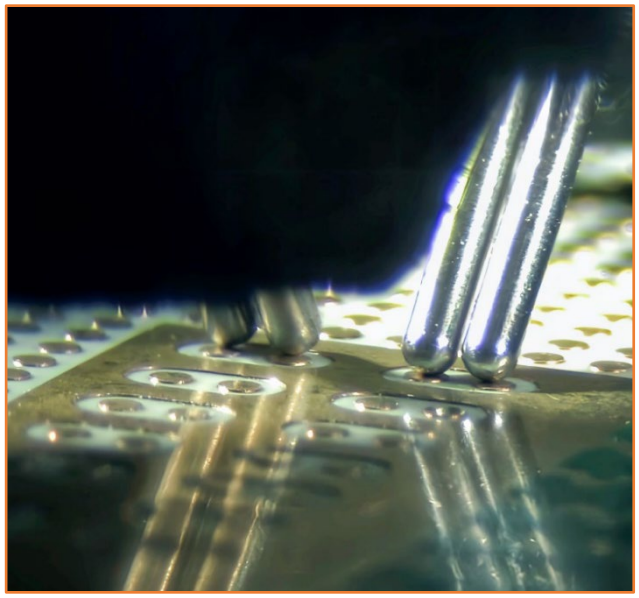
## Probe 1 mm pitch differential face-to-face PCI loopback coupons for 40 GHz to 110 GHz S-parameter analysis

Probes are placed face-to-face on test pads.

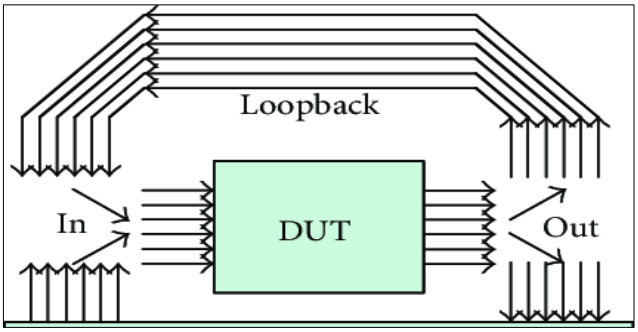



Horizontal 45° probing: Horizontally fixtured PCB
- Probe into deep test sockets or face-to-face tight-pitched test pads
- Probe can be on the left or right side
- Probe arm is in the straight position

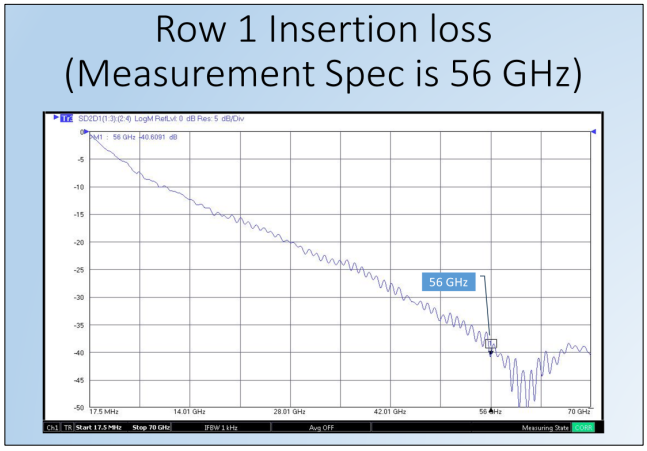
Probe tips are placed with 1 mm spacing.



Insertion loss bandwidth measurements are made on differential traces simulating the connection from the input to the output of a semiconductor device.

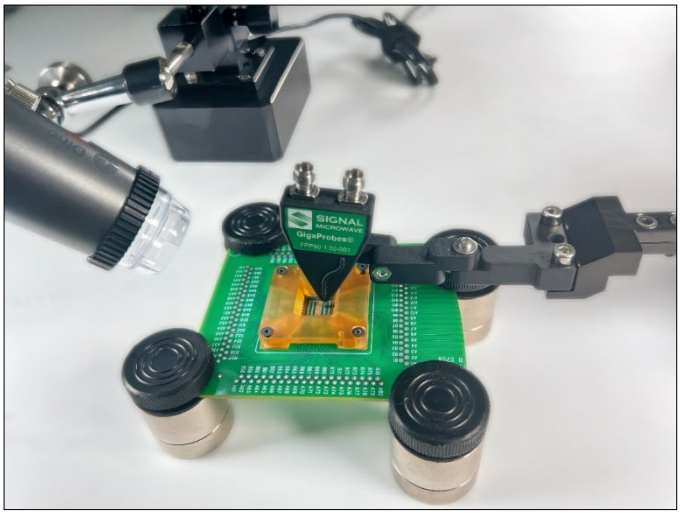



S-parameter measurement to 70 GHz



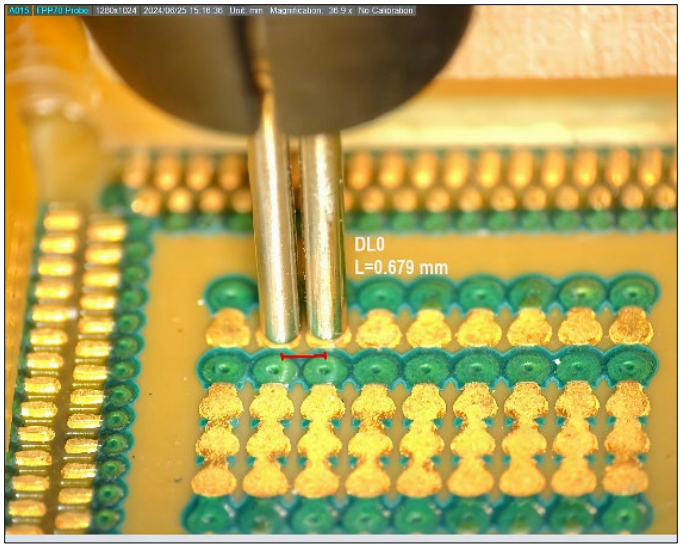
# APPLICATION

## Probe 1 mm pitch differential face-to-face PCI loopback coupons for 40 GHz to 110 GHz S-parameter analysis





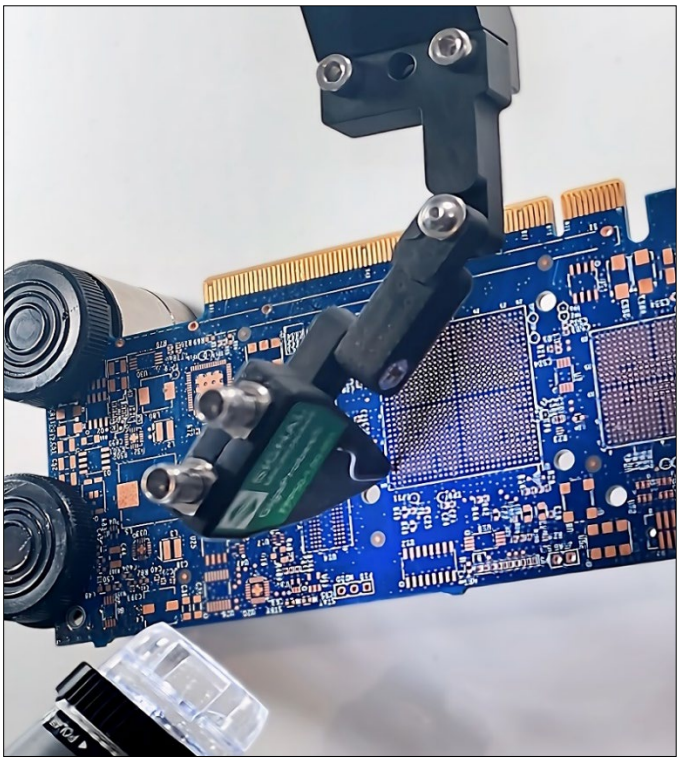
Horizontal 45° probing: Horizontally fixtured PCB
- Probe into deep test sockets or face-to-face tight-pitched test pads
- Probe can be on the left or right side
- Probe arm is in the straight position



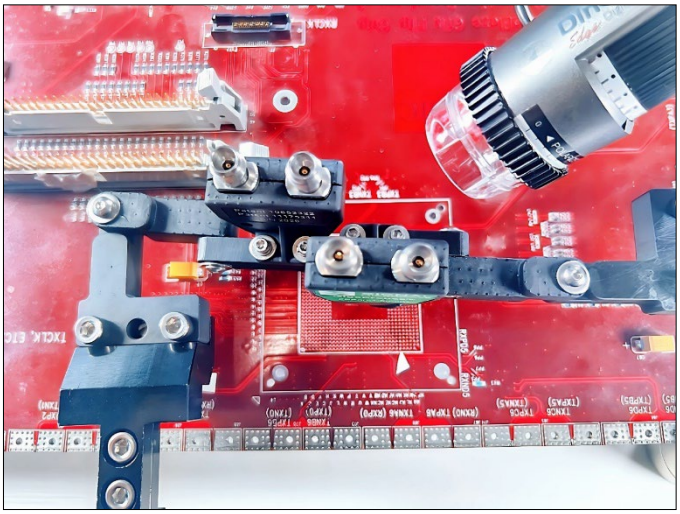

DVT-FPNN Differential rugged probe extends reach into test sockets or onto board-to-board interposers with force to make impedance and S-parameter bandwidth measurements to 70 GHz.

# APPLICATION

## Probe Test Pads at 0° to 90° or Side by Side



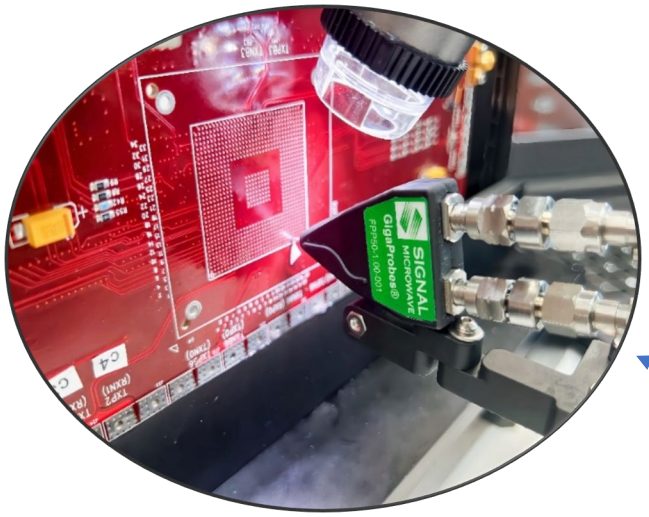
Horizontal probing: 45° oriented test pads on horizontal fixtured PCB
- Probe can be on the left or right side
- Probe straight down



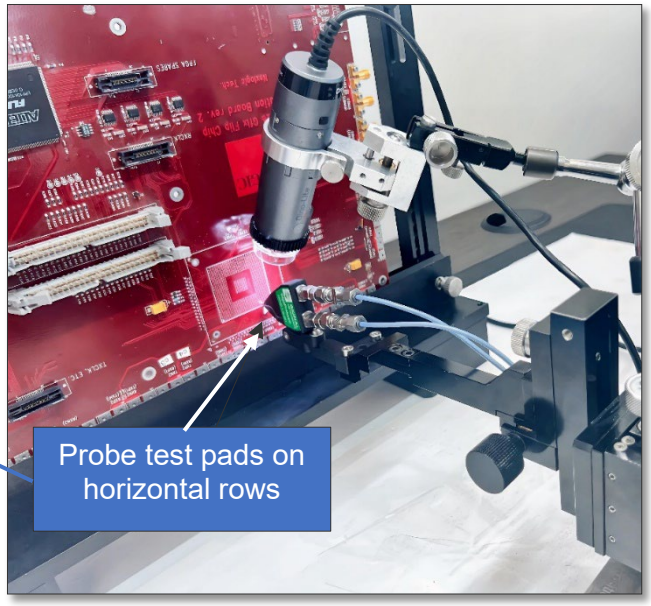
Horizontal probing: 90° oriented test pads on horizontal fixtured PCB
- Probe can be on the left or right side
- Probe straight down

# APPLICATION

## Two-sided Vertical probing of Horizontally or Vertically oriented test pads

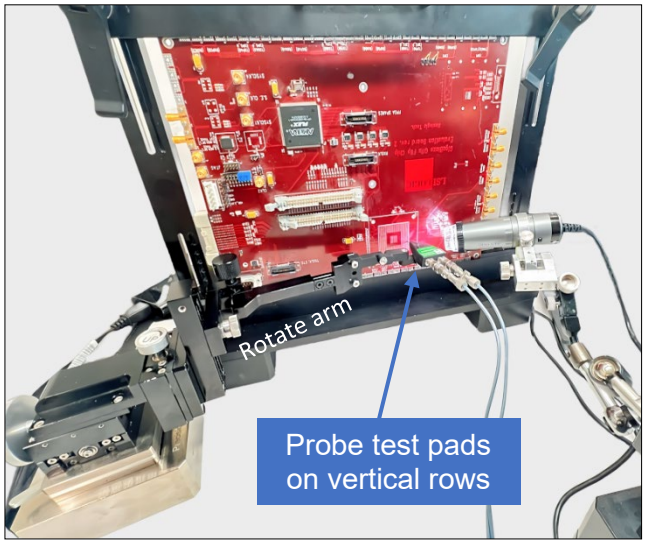




Vertical 90° Probing: Probe horizontally oriented test pads on a vertically fixtured PCB
- Probe can be on the left or right side
- Probe arm is lifted into position





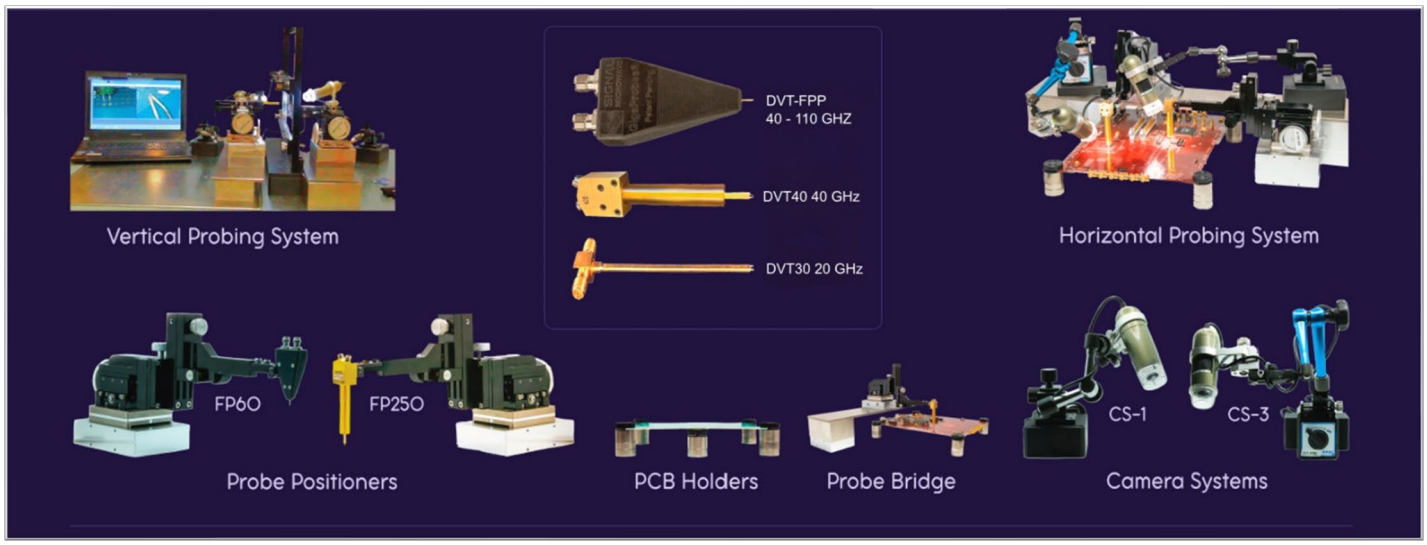
Vertical Probing: Probe Vertically oriented test pads on a vertically fixtured PCB
- Probe can be on the left or right side
- Probe arm is in straight position



# PROBE SYSTEM COMPONENTS

## Create your own custom Desktop Probing System

Select the appropriate probe bandwidth and system components to configure a probe system that meets your measurement and fixturing requirements.




For detailed descriptions and specifications for GigaProbes components, visit our website at gigaprobes.com.